

October 2008

FDD3860

N-Channel PowerTrench[®] MOSFET 100V, 29A, 36m Ω

Features

- Max $r_{DS(on)} = 36m\Omega$ at $V_{GS} = 10V$, $I_D = 5.9A$
- High performance trench technology for extremely low r_{DS(on)}
- 100% UIL tested
- RoHS Compliant

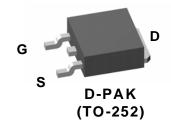


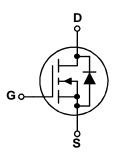
General Description

This N-Channel MOSFET is rugged gate version of Fairchild Semiconductor's advanced Power Trench® process. This part is tailored for low $r_{DS(on)}$ and low Qg figure of merit, with avalanche ruggedness for a wide range of switching applications.

Applications

- DC-AC Conversion
- Synchronous Rectifier





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	Parameter			Units
V _{DS}	Drain to Source Voltage			100	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Silicon limited)	T _C = 25°C		29	
I _D	-Continuous	T _A = 25°C	(Note 1a)	6.2	Α
	-Pulsed			60	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	121	mJ
D	Power Dissipation	T _C = 25°C		69	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	3.1	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	40	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD3860	FDD3860	D-PAK (TO-252)	13"	12mm	2500 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C		98		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	3.8	4.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, referenced to 25°C		-11.4		mV/°C
-	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 5.9A$		29	36	mΩ
r _{DS(on)} Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 5.9A, T_J = 125$ °C		51	64	11122	
9 _{FS}	Forward Transconductance	$V_{DS} = 10V, I_D = 5.9A$		20		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 50V V 0V	1310	1740	pF
C _{oss}	Output Capacitance	$V_{DS} = 50V, V_{GS} = 0V,$ f = 1MHz	100	130	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112	45	70	pF
R_g	Gate Resistance	f = 1MHz	1.6		Ω

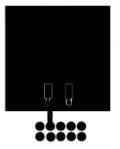
Switching Characteristics

t _{d(on)}	Turn-On Delay Time	.,		16	29	ns
t _r	Rise Time	$V_{DD} = 50V$, $I_{D} = 5.9A$, $V_{GS} = 10V$, $R_{GEN} = 6Ω$		10	21	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = 10V, K _{GEN} = 652		24	39	ns
t _f	Fall Time			7	15	ns
Q_{g}	Total Gate Charge at 10V			22	31	nC
Q_{gs}	Gate to Source Charge	$V_{DD} = 50V, I_{D} = 5.9A$		7.1		nC
Q_{gd}	Gate to Drain "Miller" Charge			6.3		nC

Drain-Source Diode Characteristics

1 Source to Drain Dioge Forward Voltage	Source to Drain Diade Forward Voltage	$V_{GS} = 0V, I_S = 2.0A$ (Note 2)	0.7	1.2	V
	$V_{GS} = 0V, I_S = 5.9A$ (Note 2)	0.8	1.3	V	
t _{rr}	Reverse Recovery Time	I _E = 5.9A, di/dt = 100A/μs	34	55	ns
Q _{rr}	Reverse Recovery Charge	T _F = 5.9A, di/dt = 100A/μs	40	64	nC

R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.



a) 40°C/W when mounted on a 1 in² pad of 2 oz copper



b) 96°C/W when mounted on a minimum pad.

- 2: Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3: Starting T_J = 25°C, L = 3mH, I_{AS} = 9A, V_{DD} = 100V, V_{GS} = 10V.

Typical Characteristics T_J = 25°C unless otherwise noted

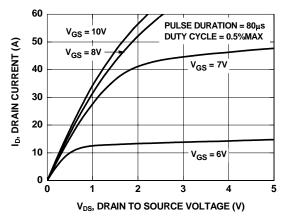


Figure 1. On-Region Characteristics

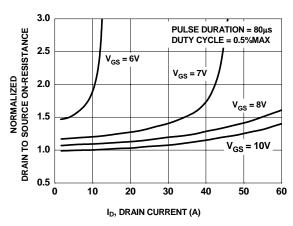


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

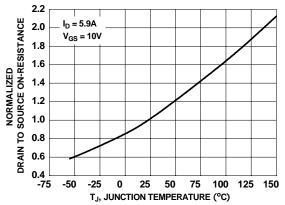


Figure 3. Normalized On-Resistance vs Junction Temperature

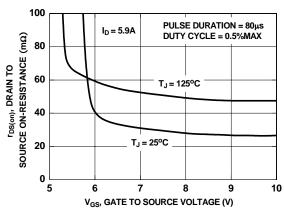


Figure 4. On-Resistance vs Gate to Source Voltage

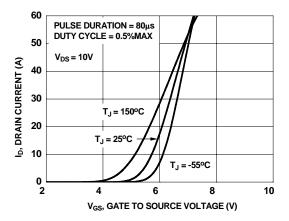


Figure 5. Transfer Characteristics

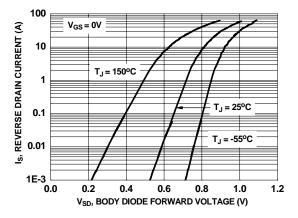


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

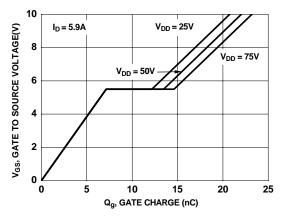


Figure 7. Gate Charge Characteristics

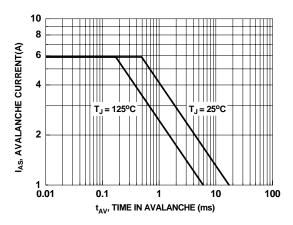


Figure 9. Unclamped Inductive Switching Capability

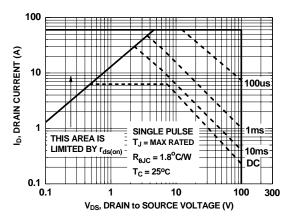


Figure 11. Forward Bias Safe Operating Area

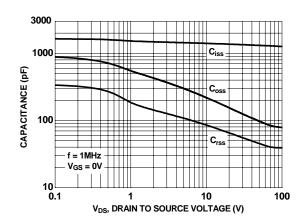


Figure 8. Capacitance vs Drain to Source Voltage

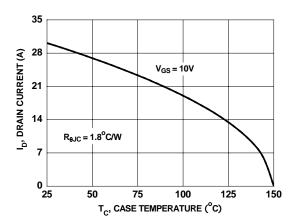


Figure 10. Maximum Continuous Drain Current vs Case Temperature

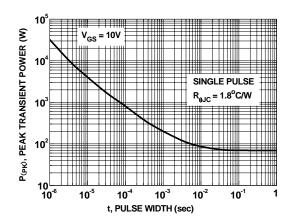


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

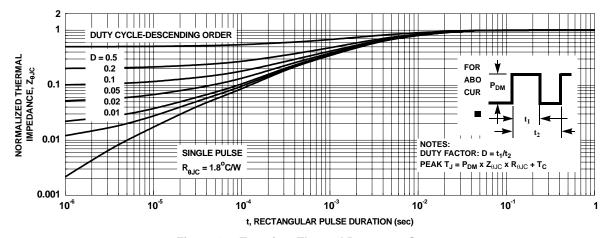


Figure 13. Transient Thermal Response Curve

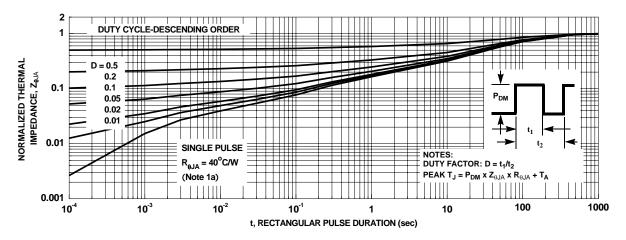


Figure 14. Transient Thermal Response Curve

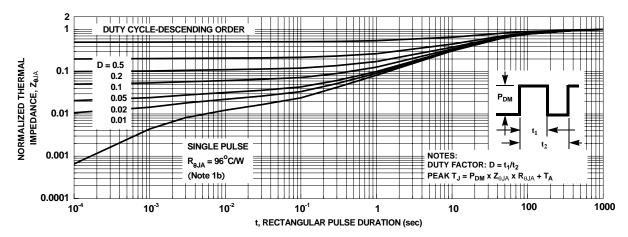


Figure 15. Transient Thermal Response Curve





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